



Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Propagation Delay Low to High X bCOM to bChy	t_{PLH} X	3003	$V_{IN}(COM)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V, V_{IH}=5V, R_L=200k\Omega$ $V_{DD}=5V, V_{SS}=V_{EE}=0V$ Note 8	-	40	ns
Propagation Delay High to Low X bCOM to bChy	t_{PHL} X	3003	$V_{IN}(COM)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V, V_{IH}=5V, R_L=200k\Omega$ $V_{DD}=5V, V_{SS}=V_{EE}=0V$ Note 8	-	40	ns
Propagation Delay Low to High 2, A to aCOM (Channels ON)	t_{PLH2} t_{PZH1}	3003	$V_{IN}(A)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V, V_{IH}=5V, V_{IN}(CH)=0V$ and 5V and Open $R_L=10k\Omega$ $V_{DD}=5V, V_{SS}=V_{EE}=0V$ Note 8	-	670	ns
Propagation Delay High to Low 2, A to aCOM (Channels ON)	t_{PHL2} t_{PHZ1}	3003	$V_{IN}(A)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V, V_{IH}=5V, V_{IN}(CH)=0V$ and 5V and Open $R_L=10k\Omega$ $V_{DD}=5V, V_{SS}=V_{EE}=0V$ Note 8	-	670	ns
Output Enable Time High Impedance to High Output 2, INH to aCOM	t_{PZH2}	3003	$V_{IN}(INH)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V, V_{IH}=5V, V_{IN}(CH)=5V, R_L=10k\Omega$ $V_{DD}=5V, V_{SS}=V_{EE}=0V$ Note 8	-	400	ns

Output Enable Time High Impedance to High Output 1, A to aCOM

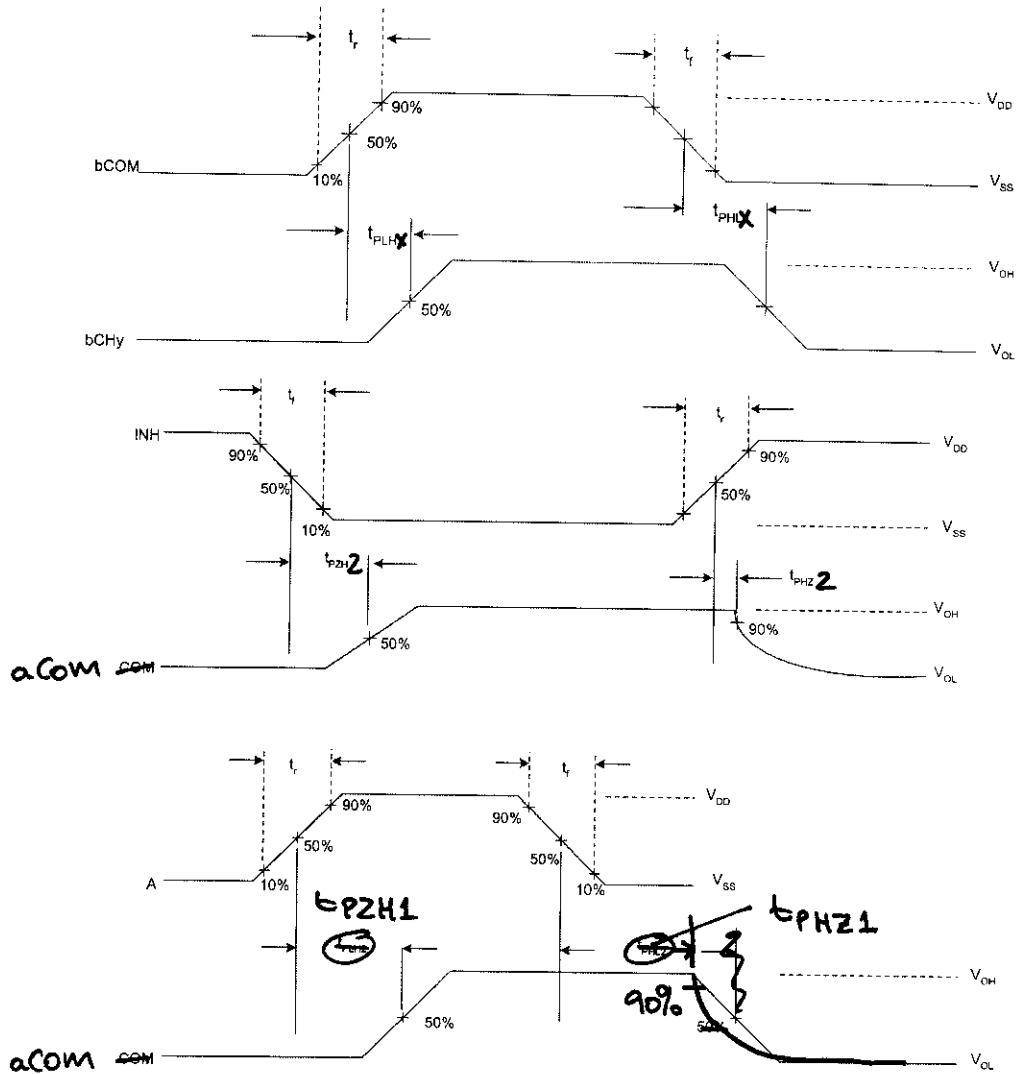
Output Disable Time High Output to High Impedance 1, A to aCOM

Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Output Disable Time High Output to High Impedance 2 , INH to aCOM	t_{PHZ} 2	3003	$V_{IN}(INH)=$ Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V, V_{IH}=5V,$ $V_{IN}(CH)=5V, R_L=300\Omega$ $V_{DD}=5V, V_{SS}=V_{EE}=0V$ Note 8	-	400	ns

2.3.2 High and Low Temperatures Electrical Measurements

The measurements shall be performed at $T_{amb}=+125 (+0 -5) ^\circ C$ and $T_{amb}=- 55(+5-0)^\circ C$.

Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Functional Test 1	-	3014	Verify Truth Table $V_{IL}=0V, V_{IH}=3V$ $V_{DD}=3V,$ $V_{SS}=V_{EE}=0V$ Note 2	-	-	-
Functional Test 2	-	3014	Verify Truth Table $V_{IL}=0V, V_{IH}=15V$ $V_{DD}=15V,$ $V_{SS}=V_{EE}=0V$ Note 2	-	-	-
Quiescent Current	I_{DD}	3005	$V_{IL}=0V, V_{IH}=15V$ $V_{DD}=15V,$ $V_{SS}=V_{EE}=0V$ Note 3 $T_{amb}=+125^\circ C$ $T_{amb}=- 55^\circ C$	-	30 1	μA
Low Level Input Current, Control Inputs	I_{IL}	3009	V_{IN} (Under Test)=0V $V_{DD}=15V,$ $V_{SS}=V_{EE}=0V$ $T_{amb}=+125^\circ C$ $T_{amb}=- 55^\circ C$	-	-100 -50	nA
High Level Input Current, Control Inputs	I_{IH}	3010	V_{IN} (Under Test)=15V $V_{DD}=15V,$ $V_{SS}=V_{EE}=0V$ $T_{amb}=+125^\circ C$ $T_{amb}=- 55^\circ C$	-	100 50	nA



2.4

PARAMETER DRIFT VALUES

Unless otherwise specified, the measurements shall be performed at $T_{amb} = +22 \pm 3^\circ C$.

The test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements.

The drift values (Δ) shall not be exceeded for each characteristic specified. The corresponding absolute limit values for each characteristic shall not be exceeded.